



MEASURING APPARATUS AND MEASURING METHOD

[0001] The present application is a continuation application of PCT/IB03/01997 filed on February 26, 2003 which claims priority from PCT/US02/05901 filed on February 26, 2002 and U.S. Patent Application Serial No. 10/265,349 filed on October 4, 2002, the contents of which are incorporated herein by reference.

BACKGROUND OF THE INVENTION

FIELD OF THE INVENTION

[0002] The present invention relates to a measuring apparatus and a measuring method for measuring an electronic device. More particularly, the present invention relates to a measuring apparatus and a measuring method that measure a jitter transfer function, a bit error rate and jitter tolerance of the electronic device under test.

RELATED ART

[0003] Jitter testing is an important item to a serial-deserial communication device. For example, Recommendations and Requirements from International Telecommunication Union and Bellcore ((1) ITU-T, Recommendation G.958: Digital Line Systems Based on the Synchronous Digital Hierarchy for Use on Optical Fibre Cables, November 1994, (2) ITU-T, Recommendation O.172: Jitter and Wander Measuring Equipment for Digital Systems Which are Based on the Synchronous Digital Hierarchy (SDH), March 1999, (3) Bellcore, Generic Requirements GR-1377-Core: SONET OC-192 Transport System Genetic Criteria, December 1998) define